Notice of References Cited

Application/Control No. 10/727,924	Reexamination	Applicant(s)/Patent Under Reexamination HUANG ET AL.		
Examiner	Art Unit			
Joannie A García	2823	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,686,345	11-1997	Harmon et al.	438/702
	В	US-6,150,211	11-2000	Zahurak, John K.	438/244
	С	US-6,352,931	03-2002	Seta et al.	438/700
	D	US-2002/0039836	04-2002	Venkatesan et al.	438/622
	E	US-6,528,428	03-2003	Chen et al.	438/700
	F	US-6,605,542	08-2003	Seta et al.	438/700
	G	US-6,821,913	11-2004	Chuang et al.	438/786
	Н	US-2001/0023956	09-2001	Collins et al.	257/301
	ı	US-6,504,107	01-2003	Kragl, Hans	174/260
	J	US-2002/0127803	09-2002	Schlosser et al.	438/258
	К	US-2003/0068867	04-2003	Forster et al.	438/386
	L	US-6,734,077	05-2004	Forster et al.	438/386
	М	US-2004/0095896	05-2004	Chudzik et al.	370/254

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	٧				
	w				
	х				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.